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Sommario/riassunto

This book presents reviews of various aspects of radiation/matter interactions, be these instrumental developments, the application of the study of the interaction of X-rays and materials to a particular scientific field, or specific methodological approaches. The overall aim of the book is to provide reference summaries for a range of specific subject areas within a pedagogical framework. Each chapter is written by an author who is well known within their field and who has delivered an invited lecture on their subject area as part of the "RX2009 - X-rays and Materials" colloqui